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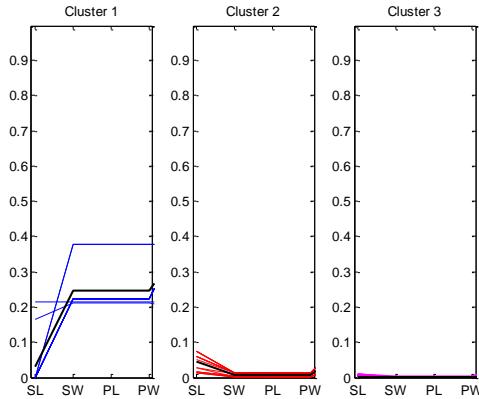
Figure 7: Grouping of different data values in clusters (here 3 clusters consider in our approach)
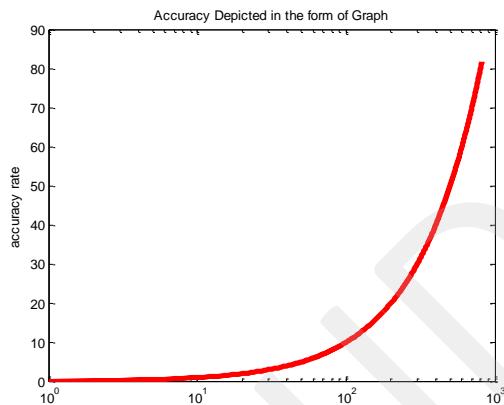

Figure 8: Accuracy rate in our classification approach for a given dataset in semilogy plot.

The accuracy of a measurement system is the degree of closeness of measurements of a quantity to that quantity's actual (true) value. In our approach, the achieved accuracy is approximately 81.8182 %, if we draw a semilogy plot with this accuracy value the plot is look as shown in figure 9. Semilogy plots data with logarithmic scale for the y-axis. Semilogy of data creates a plot using a base 10 logarithmic scale for the y-axis and a linear scale for the x-axis. It plots the columns of Y versus their index if Y contains real numbers. "Semilogy (data)" is equivalent to "semilogy (real (data), imag (data))" if Y contains complex numbers. Semilogy ignores the imaginary component in all other uses of this function.

VII. References

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